



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 6

Test carried on 13.12.11 – 14.12.11

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	15	4000	2.05	n.c.	2.05	n.c.	6724	
B	104	4000	1.97	n.c.	2.03	n.c.	6678	
C	35	4000	1.98	n.c.	1.93	n.c.	6293	
D	134	4000	2.28	n.c.	2.18	n.c.	6505	
E	34	3500	2.03	n.c.	2.00	n.c.	6666	
F	32	4000	2.03	n.c.	1.99	n.c.	6440	
G	90	3500	2.07	n.c.	1.99	n.c.	6210	

Operational Temperature: -169.2 °C

Date: 14.12.2011

Tested by:
/I.Kojouharov/

Assembly and test remarks:

Regular test after assembly at RIKEN

Channels A(HEX 15) and F(HEX 32) possible use at 4500 V if needed.

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau = 6 \mu\text{s}$, Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source - ^{60}Co